# SMD Type Power Inductor

FPI0504F-101K

		ECN HISTORY	LIST		
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	14/01/14	新 發 行	楊祥忠	陳金源	徐允珮
備					
註					

TAI-TECH P2

## **SMD Type Power Inductor**

FPI0504F-101K

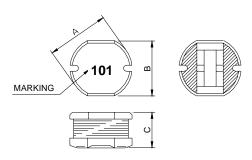
#### 1. Features

- 1.Excellent solderability and high heat resistance.
- 2. Excellent terminal strength construction.
- 3. Packed in embossed carrier tape and can be used by automatic mounting machine.
- 4.100% Lead(Pb) & Halogen-Free and RoHS compliant.





#### 2. Dimension



Size	A(mm)	B(mm)	C(mm)
FPI 0504	5.80±0.3	5.20±0.3	4.50±0.3

Unit:mm

### 3. Part Numbering



A: Series

B: Dimension

C: Lead free type

D: Inductance 101=100uH E: Inductance Tolerance K=±10%

### 4. Specification

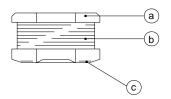
TAI-TECH Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) max.	IDC (A) max.
FPI 0504F-101K	100	±10%	1V/1K	0.70	0.60

<sup>\*</sup> IDC Test

For the parts with inductance under 82 uH, the L is measured at 1MHz then when a IDC current is applied, the L should drop less than 35%. For the parts with inductance over 100 uH, the L is measured at 1KHz then when a IDC current is applied, the L should drop less than 35%.

For all FPI series ,when a IDC current is applied, the temperature rised of the parts is less than 40 degree C

#### 5. Material List



No.	Item	Material Ferrite DR Core Enamelled Copper wire	
1	Core	Ferrite DR Core	
2	Wire	Enamelled Copper wire	
3	Terminal	Ag+Ni+Sn	

#### 6. Schematic Diagram

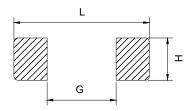


TAI-TECH P3

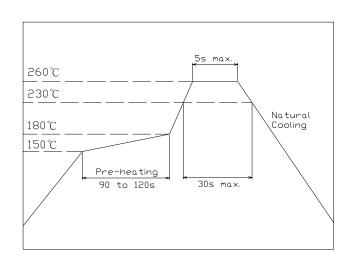
### 7. Reliability and Test Condition

Item	Performance	Test Condition
Operating Temperature	-25~+85°C	
Storage temperature	-25~+85℃(For products in unopened tape package, less than 40℃)	
Rated Current	Base on temp. rise & △L/LOA≦35%	
Temperature Rise Test	40°C typ. (∆t)	
Solderability	More than 90% of the terminal electrode shall be covered with fresh solder.	Preheat : 150±25°C for 60 secs Solder : Sn-Ag3.0-Cu0.5 Solder Temp.:245±5°C Flux : Rosin Dip Time : 4±1 secs
Thermal Shock Test (Temp. Cycle) MIL-STD-202G METHOD 107	Inductance shall not change more than ±10%	ROOM TEMP.   -55±2°C     30 MINUTES
Humidity Resistance Test MIL-STD-202G METHOD 103	Inductance shall not change more than ±10%	Temperature : 40±2°C Humidity : 90~95% Applied Current : per spec. Time : 500±8 hrs
High Temperature Resistance Test MIL-STD-202G METHOD 108	Inductance shall not change more than ±10%	Temperature: 85±2°C Applied Current: per spec. Time: 500±8 hrs
Random Vibration Test	Appearance: Cracking, shipping and any other defects harmful to the characteristics should not be allowed.  Inductance: within±30%	Frequency: 10-55-10Hz for 1 min. Amplitude: 1.52mm Directions and times: X, Y, Z directions for 2 hours. A period of 2 hours in each of 3 mutually perpendicular directions (Total 6 hours).

### 8. Recommended PC Board Pattern

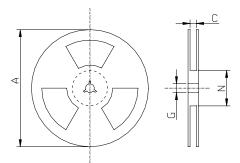


L(mm)	G(mm)	H(mm)		
5.5	1.9	5.0		

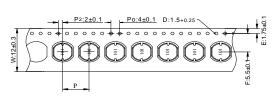


TAI-TECH P4

#### 9. Packaging Information



Style A(mm)		C(mm)	G(mm)	N(mm)
13"X12mm	330	14 <sup>+0</sup>	13.5±0.5	50 <sup>-0</sup>



Style	W(mm)	P(mm)	D(mm)	Packaging Qty(pcs)
12 mm	12±0.3	8±0.1	1.5±0.25	1,500

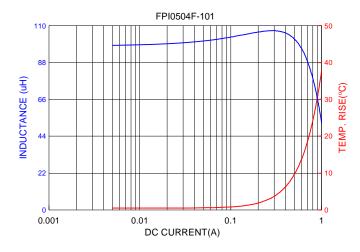
#### **Application Notice**

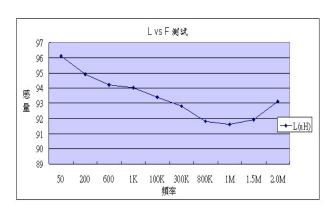
· Storage Conditions

To maintain the solderability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
  - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
  - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
  - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

#### 10. Typical Performance Curves









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以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

送樣廠商(Sample Submitted By)

西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)

樣品名稱(Sample Description)

: WINDING POWER INDUCTOR/SMD POWER INDUCTOR

樣品型號(Style/Item No.)

LQC,LQN/FPI,FPIP,FPIG SERIES

收件日期(Sample Receiving Date)

2013/06/04

測試期間(Testing Period)

: 2013/06/04 TO 2013/06/11

測試需求(Test Requested)

(1) 依據客户指定,進行鎬、鉛、汞、六價鉻、多溴聯苯,多溴聯苯醚測試. (As specified by client, to test Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs contents in the submitted sample.)

(2) 依據客户指定,進行鹵素-氟、氯、溴、碘測試. (As specified by client, to test Halogen-Fluorine, Chlorine, Bromine, Iodine contents in the

submitted sample.)

測試方法(Test Method)

: 請見下一頁 (Please refer to next pages).

測試結果(Test Results)

: 請見下一頁 (Please refer to next pages).

Edison SGS

Edison Chang/Sr. Supervisor
Signed for and on behalf on
SGS TAIWANLTH
Chemical Laboratory – Taipei

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#### 測試結果(Test Results)

測試部位(PART NAME) No.1 :

整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	参考IEC 62321: 2008方法,以感	2	n.d.
鉛 / Lead (Pb)	mg/kg	應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321;	2	n.d.
汞 / Mercury (Hg)	mg/kg	2008 and performed by ICP-AES.	2	n.d.
六價絡 / Hexavalent Chromium Cr(VI)	mg/kg	多考IEC 62321: 2008方法,以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)			50	n.d.
鹵素(氣)/ Halogen-Chlorine (C1) (CAS No.: 22537-15-1)		参考BS EN 14582:2007, 以離子層 析儀分析, / With reference to	50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 14362-44-8)			50	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs			-	n.d.
一溴聯苯 / Monobromobipheny1			5	n.d.
二溴聯苯 / Dibromobiphenyl	]		5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl	1		5	n.d.
六溴聯苯 / Hexabromobiphenyl			5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl		条者IFC 62321, 2008 安計 以為	5	n.d.
十溴聯苯 / Decabromobiphenyl			5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg			n.d.
一溴聯苯醚 / Monobromodiphenyl ether		and performed by GC/MS.	5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether			5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.

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## **Test Report**

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#### 備註(Note):

- 1. mg/kg = ppm; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限値)
- 4. "-" = Not Regulated (無規格值)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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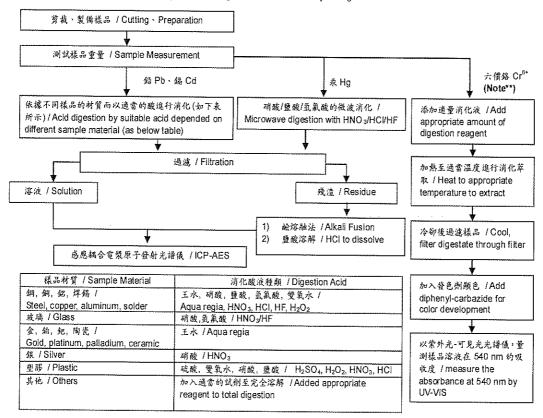
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- 根據以下的流程圖之條件,樣品已完全溶解。( 六價絡測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>5+</sup> test method excluded)
- 2) 测試人員:楊登律 / Name of the person who made measurement: Climbgreat Yang
- 3) 测试负责人:張啓典 / Name of the person in charge of measurement: Troy Chang



Note\*\*:(1) 針對非金屬材料加入鹼性消化液 '加熱至 90~95℃萃取。/ For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.

(2) 針對金屬材料加入純水,加熱至沸騰萃取 ./ For metallic material, add pure water and heat to boiling .

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# **Test Report**

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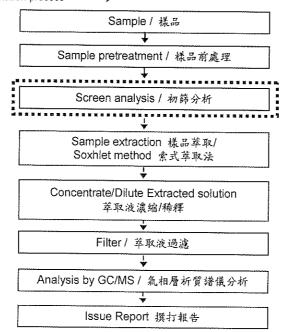
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#### 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 测試負责人:張啓興 / Name of the person in charge of measurement: Troy Chang

初次測試程序 / First testing process 
選擇性篩檢程序 / Optional screen process \*\*\*\*\*

確認程序 / Confirmation process - · - →



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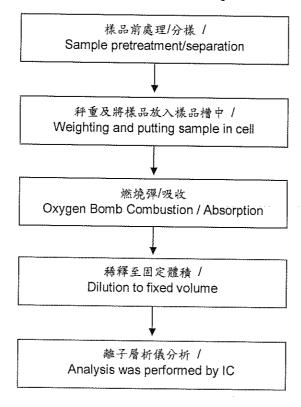
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(廣東省東莞市黄江鎮黄牛埔福祥街2號 / NO. 2, FUXIANG STREET, HUANGNIUPU, HUANGJIANG TOWN, DONGGUAN, GUANGDONG) (江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

#### 鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員:陳恩臻 / Name of the person who made measurement: Rita Chen
- 测試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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### **Test Report**

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西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)

(東莞臺慶精密電子有限公司 / TAI-TECH ADVANCED ELECTRONICS (DONGGUAN) CO. LTD.)

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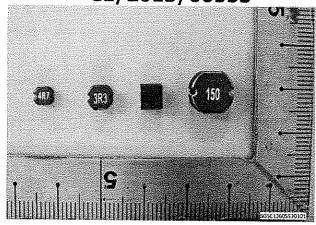
桃園縣楊梅市幼獅工業區幼四路1之1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI CITY, TAO-YUAN HSIEN. TAIWAN R. O. C.

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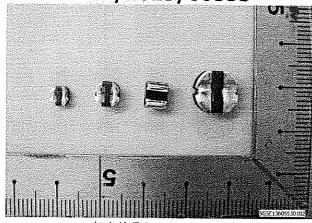
#### \* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位。\*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2013/60553



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\*\* 報告結尾(End of Report) \*\*

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